PTO/SB/08A (08-03)

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JUL 0 9 2004 ork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number. Complete if Known m 1449A/PTO SHEW B Application Number 10/796,195 INFORMATION DISCLOSURE Filing Date 03/10/2004 STATEMENT BY APPLICANT First Named Inventor Kato, et al. TBD Art Unit

Sheet		1	of	Attorney	Docket Number 5	20.30414C56
				U.S. PATENT	DOCUMENTS	
Examiner Initials'	Cite No.	Document Numb Number-Kind Code ² (# kn		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Docume	Pages, Columns, Lines, Where ent Relevant Passages or Relevant Figures Appear
KSO		US- 5,536,128		7/16/1996	Shimoyashiro, et al.	
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Examiner Initials'	Cite No.	Foreign Patent Document Country Code * Number * Hind Code * (If known) 1P 64-036042	Publication Date MM-DD-YYYY 2/7/1989	Name of Patentee or Applicant of Cited Document Kokusai Electric Co., Ltd.	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Τ°
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Examiner Initials*	Cite, No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Τ²
KSO		S. Nakagawa, "Dry Etching", Drafts in Symposium of VLSI and FA Technology, April 1985, pages 1-14	
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Applicant is unique citation designation number (optional). Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CFR 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentially is governed by 35 CFR 1.98. The information is required to estimated to take 120 initionates to complete, including eathering, preparing, and submitting the completed application from to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing the this burden, should be sent to the Chief Information Officer, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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November 20, 2002

Decision on Opposition No. 2001.72518 relating to JP 3145375, Patentee Hitachi, Ltd., pages 1-28, November 20, 2002

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Decision on Opposition No. 2001.72574 relating to JP 3147230, Patentee Hitachi, Ltd., pages 1-22, November 20, 2002

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